

ECE594I Notes set 9: Bipolar Transistor Noise

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References and Citations:

Sources / Citations :

Kittel and Kroemer : Thermal Physics

Van der Ziel : Noise in Solid - State Devices

Papoulis : Probability and Random Variables (hard, comprehensive)

Peyton Z. Peebles : Probability, Random Variables, Random Signal Principles (introductory)

Wozencraft & Jacobs : Principles of Communications Engineering.

Motchenbaker : Low Noise Electronic Design

Information theory lecture notes : Thomas Cover, Stanford, circa 1982

Probability lecture notes : Martin Hellman, Stanford, circa 1982

National Semiconductor Linear Applications Notes : Noise in circuits.

Suggested references for study.

Van der Ziel, Wozencraft & Jacobs, Peebles, Kittel and Kroemer

Papers by Fukui (device noise), Smith & Personik (optical receiver design)

National Semi. App. Notes (!)

Cover and Williams : Elements of Information Theory

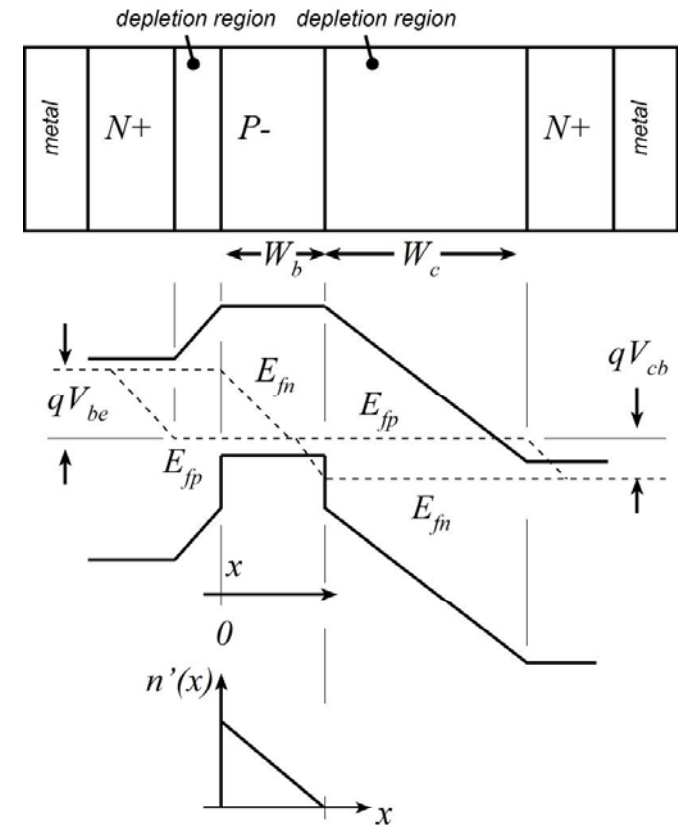
Bipolar Transistor AC Characteristics

Assume $V_{be} \gg kT/q$ and $V_{cb} \gg kT/q$.

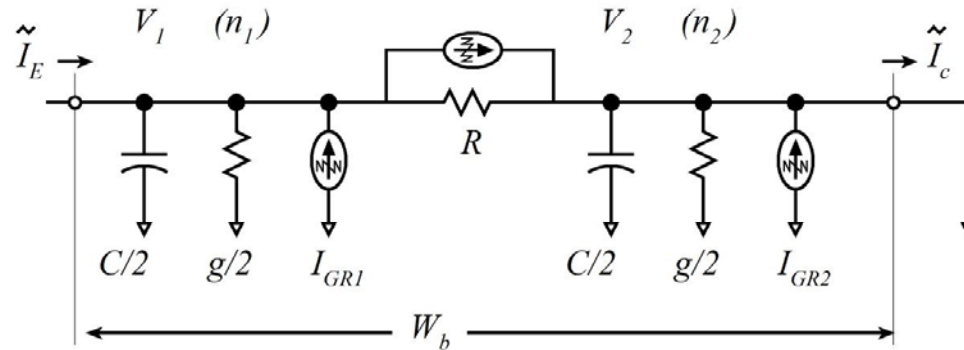
The base minority carrier concentrations are then

$$n'(0) = n(0) - n_{po} = n_{po} (e^{qV_{be}/kT} - 1) \cong n_{po} e^{qV_{be}/kT}$$

$$n'(W_b) = n_{po} (e^{-qV_{cb}/kT} - 1) \cong -n_{po} \cong 0$$



Bipolar Transistor AC Characteristics



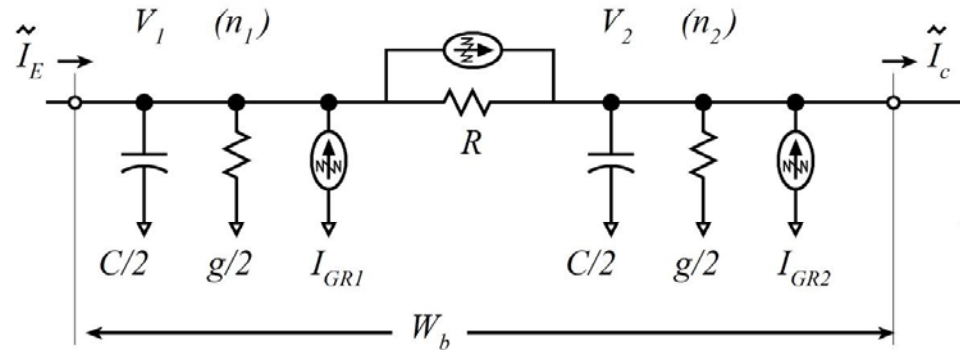
Apply the minority - carrier diffusion model :

$$G/2 = qAW_b/2 \quad C/2 = qAW_b \quad R = W_b / qAD_n$$

$$V_1 = n'_1 \cong n_{po} e^{qV_{be}/kT} \quad V_2 = n'_2 \cong 0$$

$$\tilde{S}_{I_{GR1}} = 2q \cdot \left(\frac{qn'_1 W_b A}{2\tau_R} \right) \quad \tilde{S}_{I_{GR2}} = 2q \cdot \left(\frac{qn'_1 D_n A}{W_b} \right)$$

Bipolar Transistor AC Characteristics



Note that \tilde{I}_C and \tilde{I}_E are the electron * particle * currents crossing the emitter - base and base - collector depletion regions.

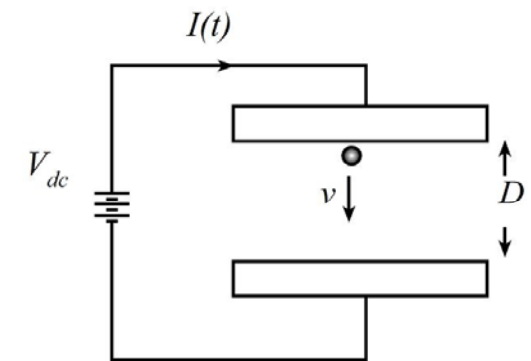
These are distinct from I_C and I_E , the total emitter and collector currents.

The distinction arises from displacement currents in the depletion regions, where the displacement currents arise from both capacitance and transit time.

BJT Characteristics: Space Charge Transit Times

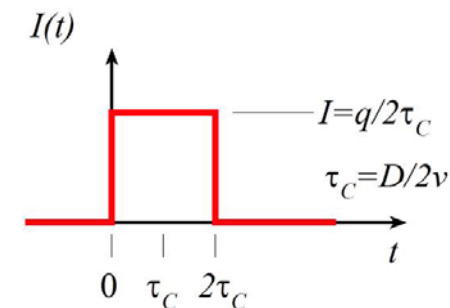
With an electron moving at velocity v between plates of a capacitor with separation d and bias voltage V_{DC} , equating the work done on the electron by moving it through the electric field $\int_{x_1}^{x_2} q\mathcal{E}(x)dx$ to the work done by the external circuit $\int_{t_1}^{t_2} V_{DC} I(t) dt$, we find

$$I(t) = \begin{cases} qv/d & \text{when the electron is moving between the plates} \\ 0 & \text{at other times.} \end{cases}$$



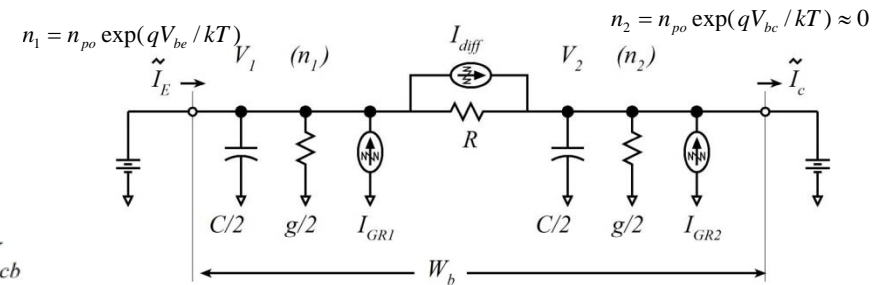
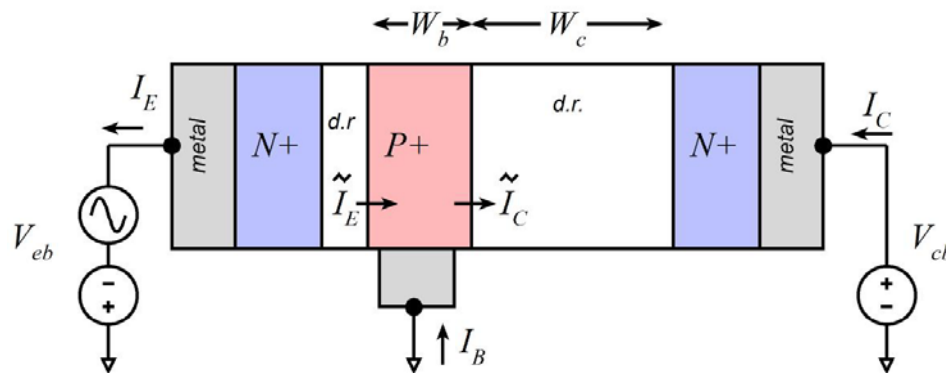
The current $I(t)$ in the external circuit is thus as shown \rightarrow

The width of this current pulse is D/v , while its mean delay (centroid) is $\tau_c = D/2v$.



For the collector depletion layer, this is the collector transit time.

BJT Characteristics: Space Charge Transit Times



Referring to the right image (diffusion diagram), forcing V_{be} and V_{ce} forces the minority carrier concentrations n_1 and n_2 at the 2 edges of the base. Electron diffusion (convention) currents \tilde{I}_E and \tilde{I}_C then flow.

From these, we must find the external circuit currents I_E , I_C and I_B .

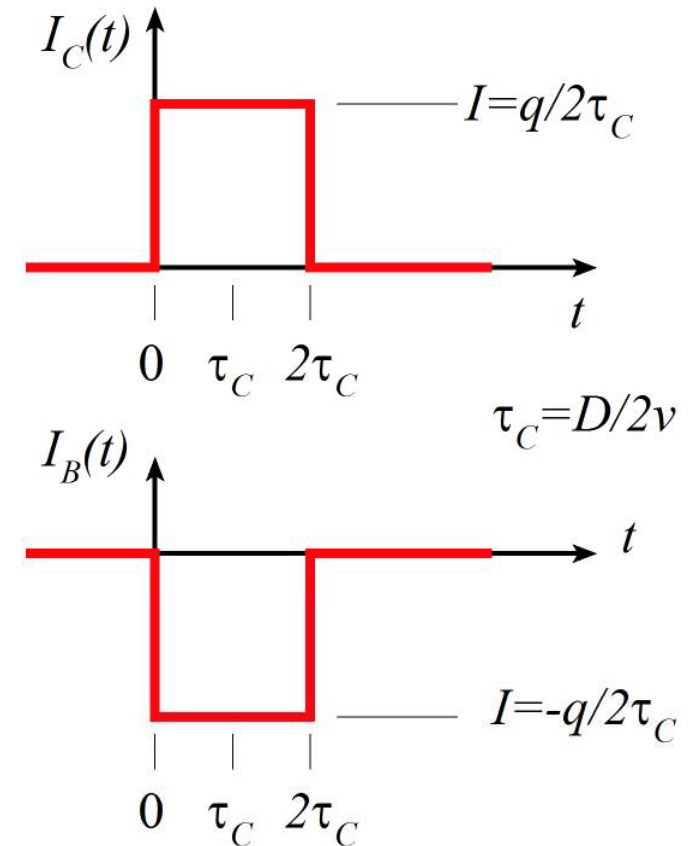
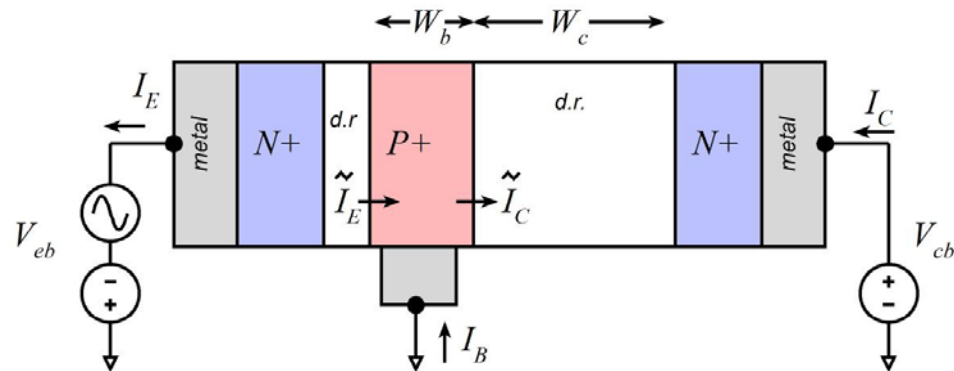
Note carefully :

\tilde{I}_E and \tilde{I}_C are defined in the directions which electrons move.

but are taken to be positive for electrons moving left to right.

I_E , I_C and I_B are defined in the directions of conventional current.

BJT Characteristics: Space Charge Transit Times



If a single electron enters the cb depletion region from the base, then the collector convection current is

$$\tilde{I}_C(t) = q \cdot \delta(t),$$

while the collector terminal current is

$$I_C(t) = \begin{cases} q/2\tau_c & 0 < t < 2\tau_c \\ 0 & \text{otherwise.} \end{cases}$$

The base terminal current is of the opposite sign

$$I_B(t) = \begin{cases} -q/2\tau_c & 0 < t < 2\tau_c \\ 0 & \text{otherwise.} \end{cases}$$

Similar analysis applies to the eb depletion layer, but the EB transit time will be here neglected. In our THz HBT work, we do not make this assumption.

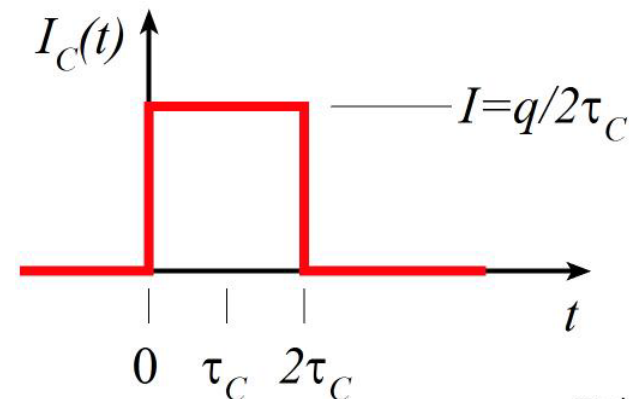
BJT Characteristics: Space Charge Transit Times

The Fourier transform of a rectangular pulse

$$h(t) = \begin{cases} 1/2\tau_c & 0 < t < 2\tau_c \\ 0 & \text{otherwise.} \end{cases}$$

is $h(j\omega) = e^{-j\omega\tau_c} \cdot (\sin(\omega\tau_c)/\omega\tau_c)$.

Approximating to 1st order in $\omega\tau_c$: $h(j\omega) \cong (1 - j\omega\tau_c) \cong (1 + j\omega\tau_c)^{-1} \cong e^{-j\omega\tau_c}$.



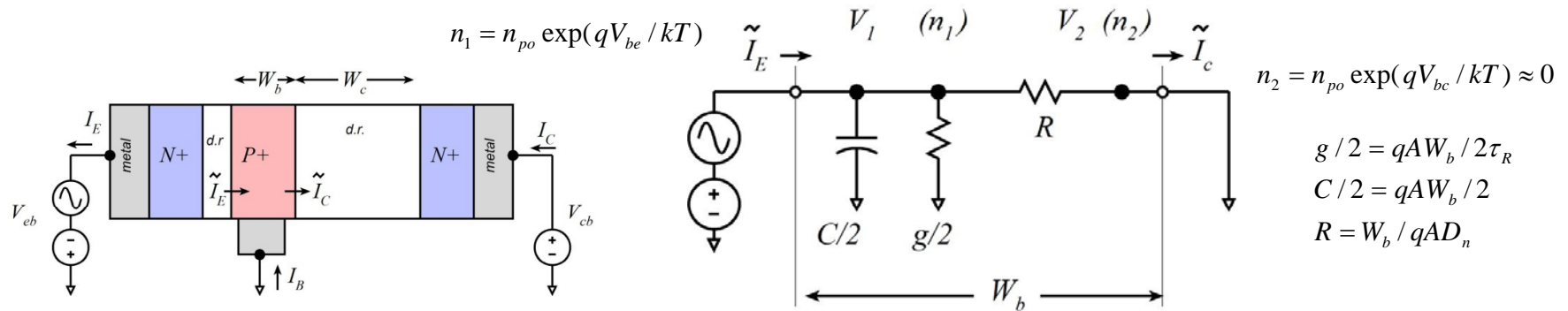
The terminal currents can then be related to the convection currents :

$$I_C \cong \tilde{I}_C \cdot (1 - j\omega\tau_c) \cong \tilde{I}_C \cdot (1 + j\omega\tau_c)^{-1} \quad \text{collector terminal current}$$

$$I_E \cong \tilde{I}_E \quad \text{emitter terminal current}$$

$$I_B = I_E - I_C \cong I_E - \tilde{I}_C \cdot (1 - j\omega\tau_c) \quad \text{base terminal current}$$

BJT Small-Signal Characteristics (no noise)



Ignore g (base recombination) to simplify analysis.

$$\delta \tilde{I}_E = \delta n_1 \cdot (1/R + j\omega C/2) = \delta n_1 \cdot (qAD_n / W_b + j\omega \cdot qAW_b / 2)$$

$$\delta \tilde{I}_C = (qAD_n / W_b) \cdot \delta n_1$$

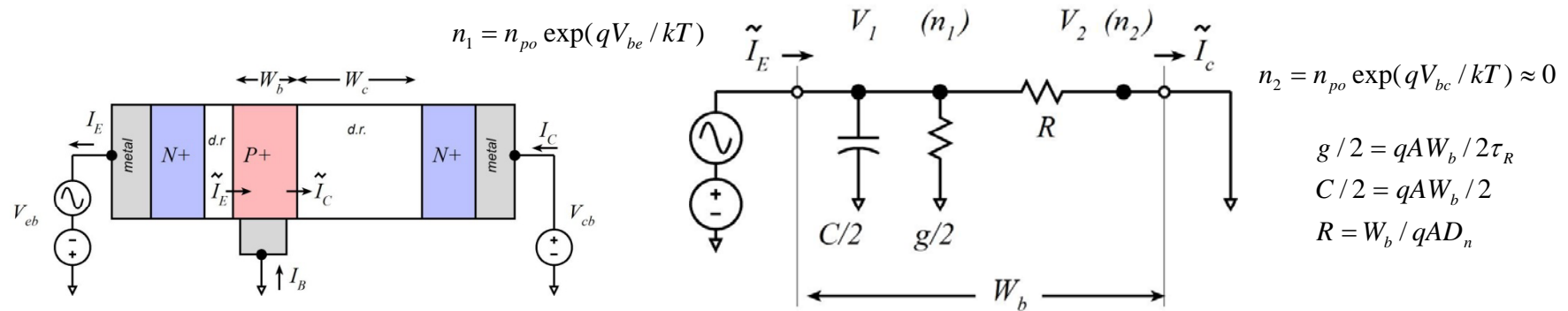
But $\delta n_1 = (q/kT) \cdot \delta V_{be}$, while at DC,

$$\delta \tilde{I}_E (\omega \rightarrow 0) = (qAD_n / W_b) \cdot \delta n_1 = (qAD_n / W_b) \cdot (q/kT) \cdot \delta V_{be} = (qI_{EDC} / kT) \cdot \delta V_{be}$$

$$\text{So, } \delta \tilde{I}_E = \frac{qI_{EDC}}{kT} \cdot (1 + j\omega\tau_b) \cdot \delta V_{be} \text{ and } \delta \tilde{I}_C = \frac{qI_{EDC}}{kT} \cdot \delta V_{be} \text{ where } \tau_b = W_b^2 / 2D_n$$

We now have the electron convection currents.

BJT Small-Signal Characteristics (no noise)



convection current

emitter $\delta \tilde{I}_E = \frac{qI_{EDC}}{kT} \cdot (1 + j\omega\tau_b) \cdot \delta V_{be}$

collector $\delta \tilde{I}_C = \frac{qI_{EDC}}{kT} \cdot \delta V_{be}$

terminal current

$\delta I_E \cong \delta \tilde{I}_E = \frac{qI_{EDC}}{kT} \cdot (1 + j\omega\tau_b) \cdot \delta V_{be}$

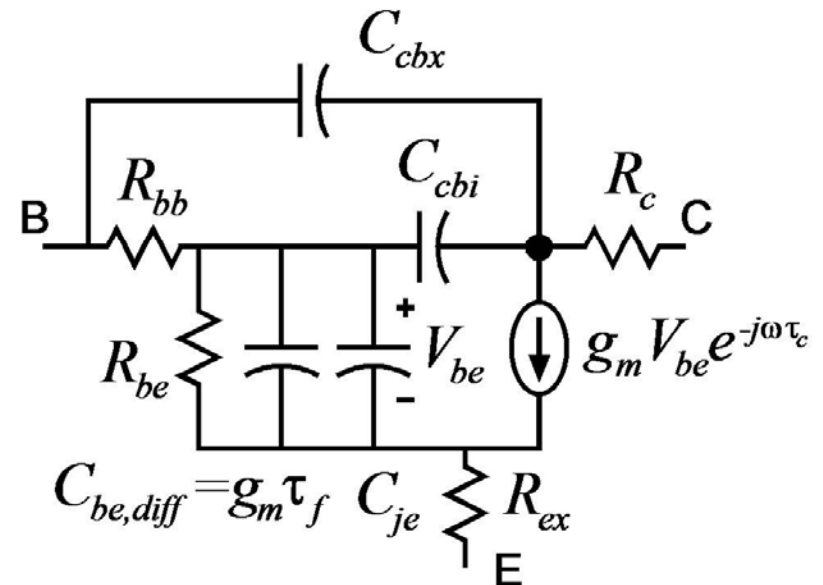
$\delta I_C \cong \delta \tilde{I}_C \cdot (1 - j\omega\tau_c) = \frac{qI_{EDC}}{kT} \cdot (1 - j\omega\tau_c) \cdot \delta V_{be}$

base terminal current :

$$\delta I_B = \delta I_E - \delta I_C \cong \frac{qI_{EDC}}{kT} \cdot (1 - j\omega\tau_c) \cdot \delta V_{be} - \frac{qI_{EDC}}{kT} \cdot (1 + j\omega\tau_b) \cdot \delta V_{be}$$

$$\delta I_B = \frac{qI_{EDC}}{kT} \cdot j\omega(\tau_b + \tau_c) \cdot \delta V_{be}$$

BJT Small-Signal Characteristics (no noise)



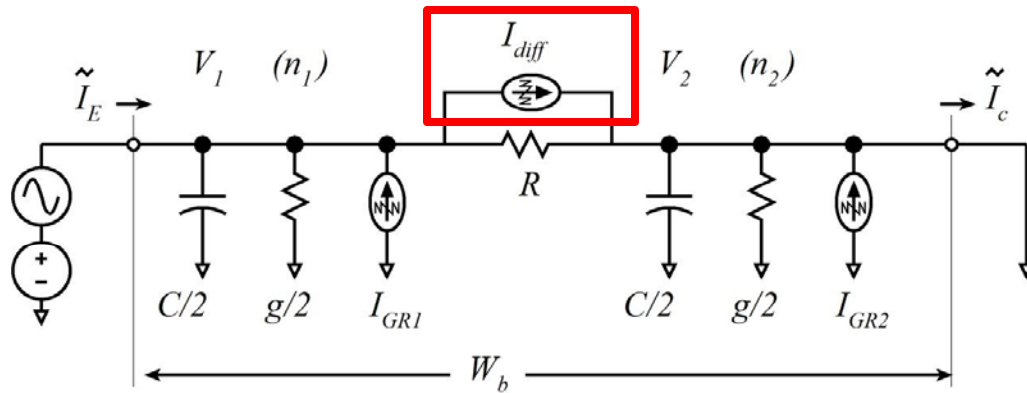
We have just derived the standard hybrid - pi model where

$$C_{diff} \cong \frac{qI_{EDC}}{kT} \cdot (\tau_b + \tau_c)$$

$$r_{be} = \frac{qI_{EDC}}{kT} \quad (\text{we lost this term by dropping } g \text{ in the diffusion analysis})$$

$$g_m \cong \frac{qI_{EDC}}{kT} \cdot (1 - j\omega\tau_c) \cong \frac{qI_{EDC}}{kT} \cdot \frac{1}{1 + j\omega\tau_c} \cong \frac{qI_{EDC}}{kT} \cdot \exp(-j\omega\tau_c)$$

BJT Noise Characteristics: Diffusion Noise



$$n_1 = n_{po} \exp(qV_{be}/kT) \quad g/2 = qAW_b/2\tau_R$$

$$n_2 = n_{po} \exp(qV_{bc}/kT) \approx 0 \quad C/2 = qAW_b/2$$

$$R = W_b/qAD_n$$

$$\tilde{S}_{I_{gr1}I_{gr1}} = 2q \cdot \frac{q(n_1' + 2n_{po})}{\tau_n} \cdot \frac{A \cdot W_b}{2}$$

$$\tilde{S}_{I_{gr2}I_{gr2}} = 2q \cdot \frac{q(n_2' + 2n_{po})}{\tau_n} \cdot \frac{A \cdot W_b}{2}$$

$$\tilde{S}_{I_{diff}I_{diff}} = 2q \cdot \frac{qAD_n}{W_b} \cdot (n_1' + n_2' + 2n_{po})$$

We consider terminal current fluctuations arising from I_{diff} * alone *.

This implies that we set the AC terminal voltages to zero.

$$\tilde{S}_{I_{diff}} = 2q \cdot \frac{qAD_n}{W_b} \cdot (n_1' + n_2' + 2n_{po}) \cong 2q \cdot \frac{qAD_n}{W_b} \cdot n_1' = 2q \cdot I_{E,DC}$$

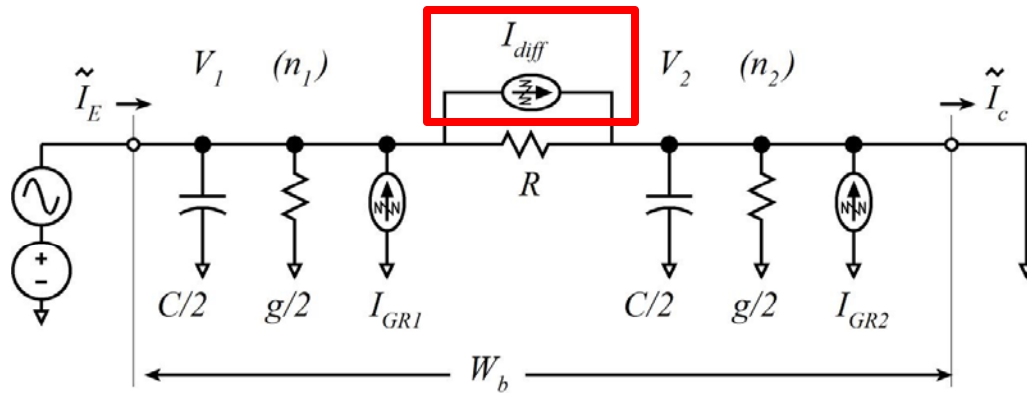
From the diffusion diagram : $\tilde{I}_C = \tilde{I}_E = I_{diff}$

We now find terminal currents :

$$I_C = \tilde{I}_C \cdot (1 - j2\pi f\tau_c) = I_{diff} \cdot (1 - j2\pi f\tau_c) =$$

$$I_E = \tilde{I}_E = I_{diff} \quad \text{and} \quad I_B = I_E - I_C = I_{diff} \cdot j2\pi f\tau_c$$

BJT Noise Characteristics: Diffusion Noise



$$n_1 = n_{po} \exp(qV_{be}/kT) \quad g/2 = qAW_b/2\tau_R$$

$$n_2 = n_{po} \exp(qV_{bc}/kT) \approx 0 \quad C/2 = qAW_b/2$$

$$R = W_b/qAD_n$$

$$\tilde{S}_{I_{gr1}I_{gr1}} = 2q \cdot \frac{q(n_1' + 2n_{po})}{\tau_n} \cdot \frac{A \cdot W_b}{2}$$

$$\tilde{S}_{I_{gr2}I_{gr2}} = 2q \cdot \frac{q(n_2' + 2n_{po})}{\tau_n} \cdot \frac{A \cdot W_b}{2}$$

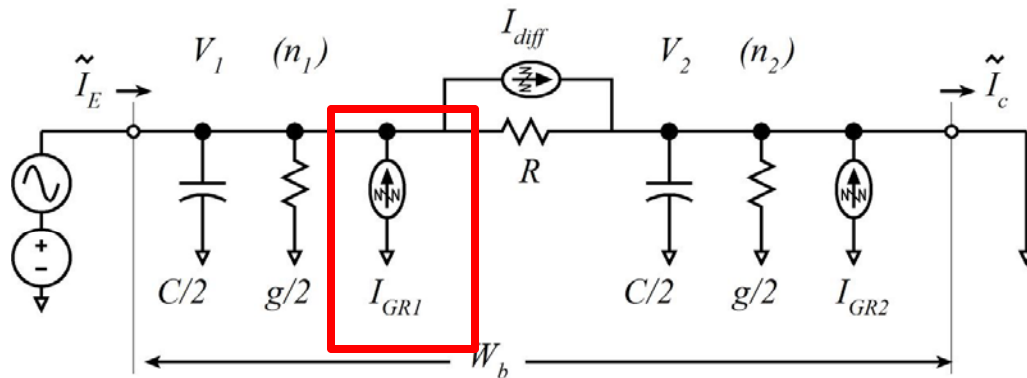
$$\tilde{S}_{I_{diff}I_{diff}} = 2q \cdot \frac{qAD_n}{W_b} \cdot (n_1' + n_2' + 2n_{po})$$

$$\tilde{S}_{I_C} = 2qI_{E,DC} \cdot (1 + (2\pi f\tau_c)^2) = 2qI_{E,DC} \text{ as our analysis is 1st order in } (2\pi f\tau_c).$$

$$\tilde{S}_{I_B} = (2\pi f\tau_c)^2 \cdot \tilde{S}_{I_{diff}} = (2\pi f\tau_c)^2 \cdot 2qI_{E,DC}$$

$$\tilde{S}_{I_B I_C} = j2\pi f\tau_c \cdot \tilde{S}_{I_{diff}} = j2\pi f\tau_c \cdot 2qI_{E,DC}$$

BJT Noise Characteristics: Recombination Noise



$$n_1 = n_{po} \exp(qV_{be}/kT) \quad g/2 = qAW_b/2\tau_R$$

$$n_2 = n_{po} \exp(qV_{bc}/kT) \approx 0 \quad C/2 = qAW_b/2$$

$$R = W_b/qAD_n$$

$$\tilde{S}_{I_{gr1}I_{gr1}} = 2q \cdot \frac{q(n_1' + 2n_{po})}{\tau_n} \frac{A \cdot W_b}{2}$$

$$\tilde{S}_{I_{gr2}I_{gr2}} = 2q \cdot \frac{q(n_2' + 2n_{po})}{\tau_n} \frac{A \cdot W_b}{2}$$

$$\tilde{S}_{I_{diff}I_{diff}} = 2q \cdot \frac{qAD_n}{W_b} \cdot (n_1' + n_2' + 2n_{po})$$

$$\tilde{S}_{I_{gr1}I_{gr1}} = 2q \cdot \frac{q(n_1' + 2n_{po})}{\tau_n} \frac{A \cdot W_b}{2} = 2q \cdot I_b (!)$$

But $\tilde{I}_E = I_{gr1}$, $I_E = \tilde{I}_E$, and $\tilde{I}_C = 0$, so

$$I_B = I_E - I_C = I_{gr1}$$

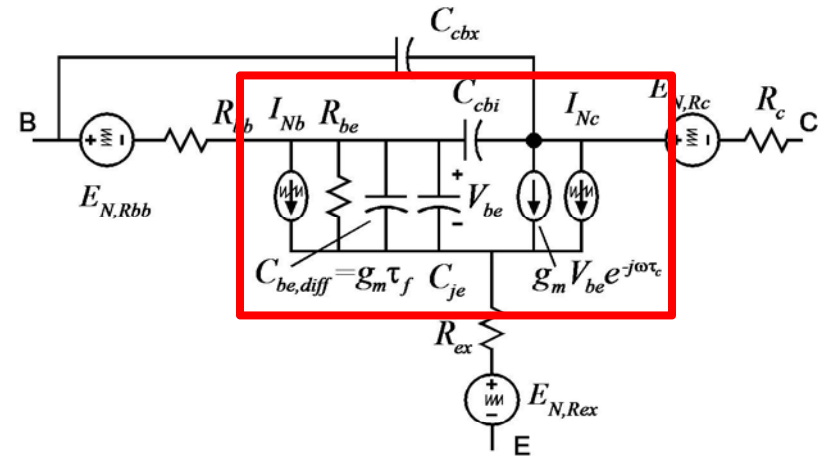
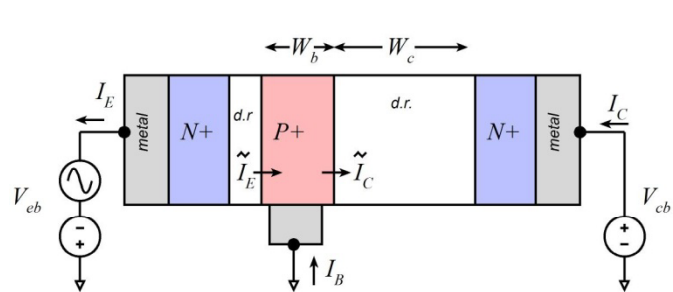
Hence

$$\tilde{S}_{I_C} = 0.$$

$$\tilde{S}_{I_B} = 2qI_B$$

$$\tilde{S}_{I_B I_C} = 0$$

BJT Noise Model For Circuit Analysis; Initial Result



We have derived our BJT noise model

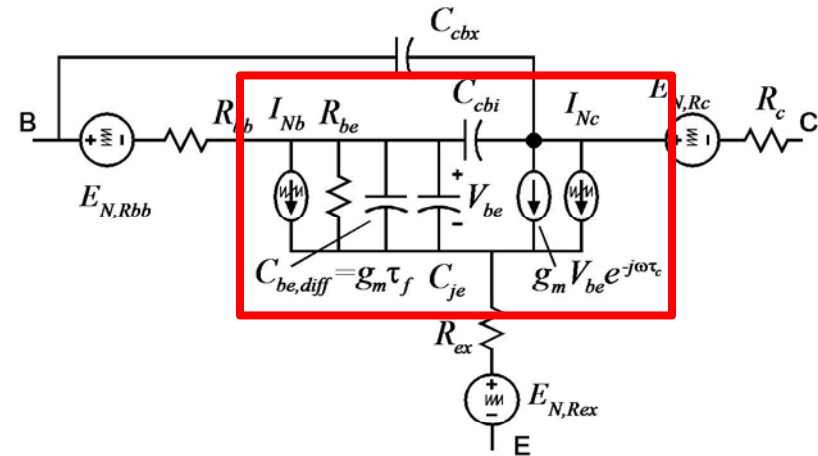
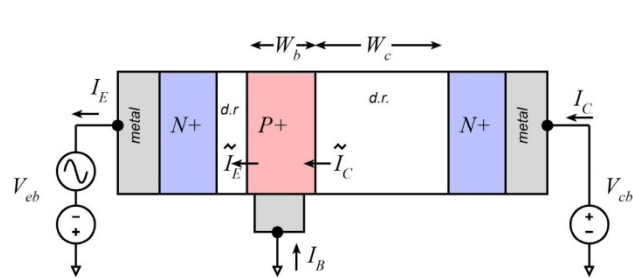
$$\tilde{S}_{I_C} = 2qI_{E,DC} \quad \tilde{S}_{I_B} = 2qI_B + (2\pi f\tau_C)^2 \cdot 2qI_{E,DC} \quad \tilde{S}_{I_B I_C} = j \cdot 2\pi f\tau_C \cdot 2qI_{E,DC}$$

The other circuit elements are

depletion capacitances

contact and bulk resistances, which have normal kT noise as indicated.

BJT Noise Model For Circuit Analysis; Reconsideration



We have found

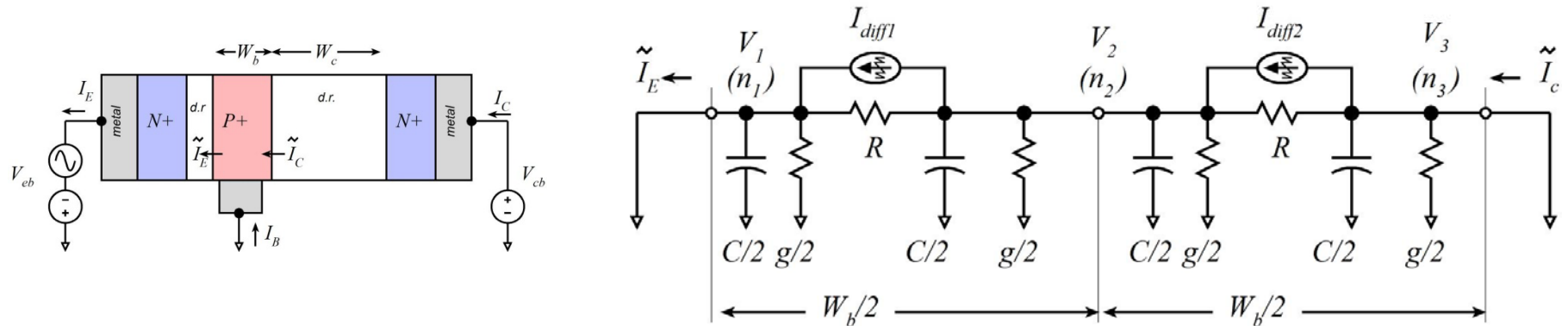
$$\tilde{S}_{I_C} = 2qI_{E,DC} \quad \tilde{S}_{I_B} = 2qI_B + (2\pi f\tau_C)^2 \cdot 2qI_{E,DC} \quad \tilde{S}_{I_B I_C} = j \cdot 2\pi f\tau_C \cdot 2qI_{E,DC}$$

It is troubling that we have found a correlation of base and collector noise due to collector transit time, but not due to base transit time.

This is a consequence of our limiting assumptions on the base transport analysis.

Let us re-do the analysis with slightly greater precision.

BJT Noise Model For Circuit Analysis; Reconsideration



We have separated the base into 2 sections. We concentrate on diffusion noise, ignoring generation/recombination noise. Note the $W_b / 2$ terms in the expressions arising from the finite elements of width $W_b / 2$.

$$n_1 = n_{po} \exp(qV_{be} / kT) \quad n_3 = n_{po} \exp(qV_{bc} / kT) \approx 0$$

$$\tilde{S}_{I_{diff1} I_{diff1}} = 2q \cdot \frac{qAD_n}{W_b / 2} \cdot (n_1' + n_2')$$

$$\tilde{S}_{I_{diff2} I_{diff2}} = 2q \cdot \frac{qAD_n}{W_b / 2} \cdot (n_2' + n_3')$$

$$g / 2 = qA(W_b / 2) / 2\tau_R$$

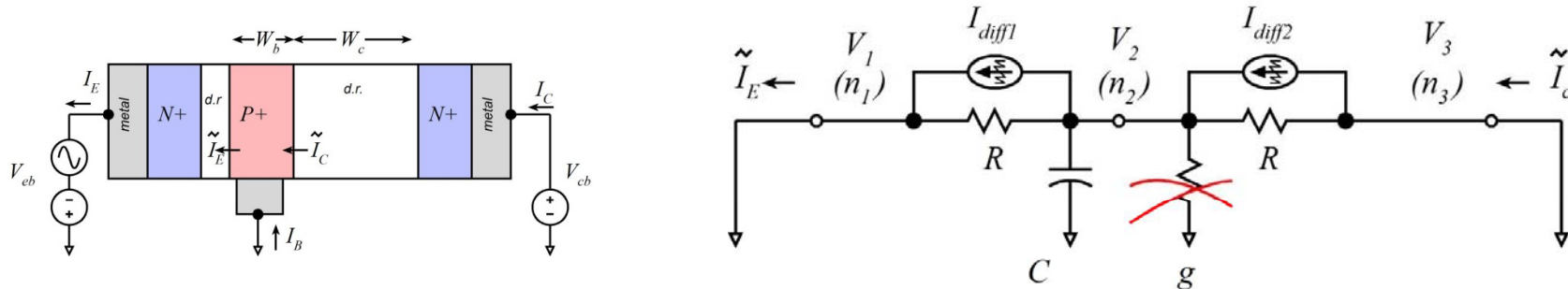
$$C / 2 = qA(W_b / 2) / 2$$

$$R = (W_b / 2) / qAD_n$$

$$\Rightarrow RC / 2 = \frac{(W_b / 2)}{qAD_n} \cdot \frac{qA(W_b / 2)}{2} = \frac{W_b^2}{8D_n} = \frac{\tau_b}{4}$$

$$n_2' \cong (n_1' + n_3') / 2$$

BJT Noise Model For Circuit Analysis; Reconsideration



Electron densities on the 2 sides of the box of width $W_b/2$ are n_1 and $n_2 = n_1/2$.

The DC diffusion currents through either box are

$$\bar{I}_{diff1} = \frac{qAD_n}{W_b/2} (n_1' - n_2') = \frac{qAD_n}{W_b/2} (n_1' - n_1'/2) = \frac{qAD_n}{W_b} n_1' = \bar{I}_E$$

$$\bar{I}_{diff2} = \frac{qAD_n}{W_b/2} (n_2') = \frac{qAD_n}{W_b/2} (n_1'/2) = \frac{qAD_n}{W_b} n_1' = \bar{I}_E$$

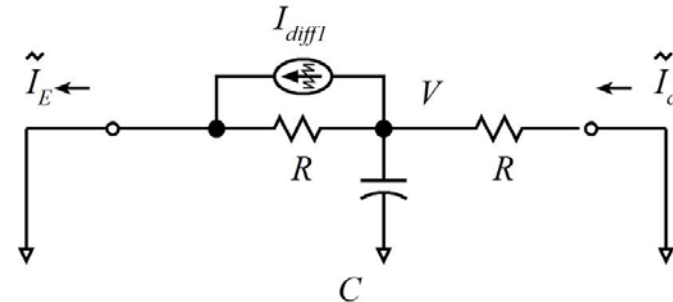
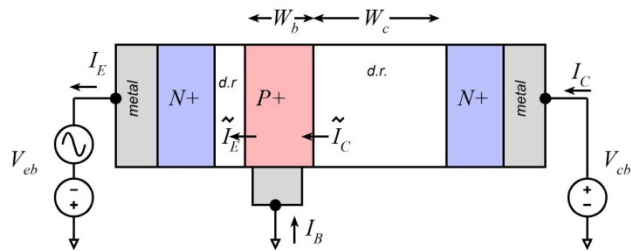
Noise current of I_{diff1} :

$$\tilde{S}_{I_{diff1}I_{diff1}} = 2q \cdot \frac{qAD_n}{W_b/2} \cdot (n_1' + n_2') = 2q \cdot \frac{qAD_n}{W_b/2} \cdot (n_1' + n_1'/2) = 2q\bar{I}_E \cdot (3)$$

Noise current of I_{diff2} :

$$\tilde{S}_{I_{diff2}I_{diff2}} = 2q \cdot \frac{qAD_n}{W_b/2} \cdot (n_2' + 0) = 2q \cdot \frac{qAD_n}{W_b/2} \cdot (n_1'/2) = 2q\bar{I}_E \cdot (1)$$

BJT Noise Model For Circuit Analysis; Reconsideration



First we calculate the emitter and collector fluxes arising from I_{diff1} , noting that $RC = \tau_b / 2$

$$V = -I_{n1} \frac{R/2}{1 + j\omega RC/2}$$

$$\tilde{I}_E = I_{N1} + V/R = I_{n1} \cdot \left[\frac{1/2 + j\omega RC/2}{1 + j\omega RC/2} \right] \cong I_{n1} \cdot [1/2 + j\omega RC/4] = I_{n1} \cdot [1/2 + j\omega \tau_b/8]$$

$$\tilde{I}_C = -V/R = I_{n1} \cdot \left[\frac{1/2}{1 + j\omega RC/2} \right] \cong I_{n1} \cdot [1/2 - j\omega RC/4] = I_{n1} \cdot [1/2 - j\omega \tau_b/8]$$

BJT Noise Model For Circuit Analysis; Reconsideration



We then calculate the emitter and collector fluxes arising from I_{diff2} , noting symmetry

$$\tilde{I}_E = I_{n2} \cdot [1/2 - j\omega\tau_b/8] \quad \text{and} \quad \tilde{I}_C = I_{n2} \cdot [1/2 + j\omega\tau_b/8]$$

Combining this with the I_{n1} transfer function :

$$\tilde{I}_E = I_{n1} \cdot [1/2 + j\omega\tau_b/8] + I_{n2} \cdot [1/2 - j\omega\tau_b/8]$$

$$\tilde{I}_C = I_{n1} \cdot [1/2 - j\omega\tau_b/8] + I_{n2} \cdot [1/2 + j\omega\tau_b/8]$$

But, from our transit time analysis : $I_C \cong \tilde{I}_C$ and $I_B \cong \tilde{I}_E - \tilde{I}_C \cdot [1 - j\omega\tau_C]$, hence

$$I_C \cong I_{n1}/2 + I_{n2}/2 + O(j\omega(\tau_b + \tau_c)) \cong I_{n1}/2 + I_{n2}/2 \quad \text{and}$$

$$I_B \cong \tilde{I}_E - \tilde{I}_C + j\omega\tau_C \cdot \tilde{I}_C$$

$$= I_{n1} \cdot [j\omega\tau_b/4] - I_{n2} \cdot [j\omega\tau_b/4] + I_{n1} \cdot j\omega\tau_C/2 + I_{n2} \cdot j\omega\tau_C/2$$

BJT Noise Model For Circuit Analysis; Reconsideration

We have found

$$I_C \cong I_{n1}/2 + I_{n2}/2 \quad \text{and} \quad I_B \cong I_{n1} \cdot \left[j\omega \left(\frac{\tau_C}{2} + \frac{\tau_b}{4} \right) \right] + I_{n2} \cdot \left[j\omega \left(\frac{\tau_C}{2} - \frac{\tau_b}{4} \right) \right]$$

where $\tilde{S}_{I_{diff1}I_{diff1}} = 2q\bar{I}_E \cdot (3)$ and $\tilde{S}_{I_{diff2}I_{diff2}} = 2q\bar{I}_E \cdot (1)$

So :

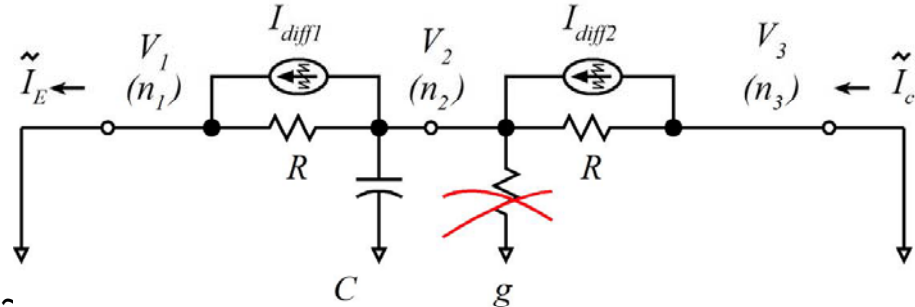
$$\tilde{S}_{I_c} = \tilde{S}_{I_{diff1}I_{diff1}} / 4 + \tilde{S}_{I_{diff2}I_{diff2}} / 4 = 2q\bar{I}_E \quad (!).$$

$$\tilde{S}_{I_B} = \left[\omega \left(\frac{\tau_C}{2} + \frac{\tau_b}{4} \right) \right]^2 \tilde{S}_{I_{diff1}I_{diff1}} + \left[\omega \left(\frac{\tau_C}{2} - \frac{\tau_b}{4} \right) \right]^2 \tilde{S}_{I_{diff2}I_{diff2}}$$

$$= 2q\bar{I}_E \cdot \left[\omega^2 \left(\tau_C^2 + \left(\frac{\tau_b}{2} \right)^2 + \frac{\tau_b\tau_C}{2} \right) \right]$$

$$\tilde{S}_{I_b I_c} \cong \left[j\omega \left(\frac{\tau_C}{2} + \frac{\tau_b}{4} \right) \right] \cdot \frac{1}{2} \tilde{S}_{I_{diff1}I_{diff1}} + \left[j\omega \left(\frac{\tau_C}{2} - \frac{\tau_b}{4} \right) \right] \cdot \frac{1}{2} \tilde{S}_{I_{diff2}I_{diff2}}$$

$$= \left[j\omega \left(\frac{\tau_C}{2} + \frac{\tau_b}{4} \right) \right] \cdot 3q\bar{I}_E + \left[j\omega \left(\frac{\tau_C}{2} - \frac{\tau_b}{4} \right) \right] \cdot q\bar{I}_E$$



BJT Noise Model For Circuit Analysis; Reconsideration

We have found

$$\tilde{S}_{I_c} = 2q\bar{I}_E \quad (!).$$

$$\tilde{S}_{I_B} = 2q\bar{I}_B + 2q\bar{I}_E \cdot \left[\omega^2 \left(\tau_C^2 + \left(\frac{\tau_b}{2} \right)^2 + \frac{\tau_b \tau_c}{2} \right) \right]$$

$$\tilde{S}_{I_b I_c} = 2q\bar{I}_E \cdot \left[j\omega \left(\tau_C + \frac{\tau_b}{4} \right) \right]$$

The derivation was long and warrants checking for errors.

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